

IGBT³ Chip

FEATURES:

- 1700V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

power module



Applications:

drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC42T170R3	1700V	29A	6.5 x 6.46 mm ²	sawn on foil	Q67050- A4151-A001

MECHANICAL PARAMETER:

Raster size	6.5 x 6.46	mm		
Emitter pad size	4.27 x 4.27			
Gate pad size	1.18 x 1.09			
Area total / active	42 / 28.7	mm ²		
Thickness	190	μm		
Wafer size	150	mm		
Flat position	180	grd		
Max.possible chips per wafer	338 pcs			
Passivation frontside	Photoimide			
Emitter metalization	3200 nm AlSiCu			
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, <500μm			
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _j =25 °C	V _{CE}	1700	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	87	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i arameter			min.	typ.	max.]
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0 V , I_{C} = 1.5 mA	1700			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =29A	1.6	2	2.4	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I_C =1.2mA , V_{GE} = V_{CE}	5.2	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V _{CE} =1700V , V _{GE} =0V			2	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	R _{Gint}			8		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	bol Conditions	Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Onne
Input capacitance	Ciss	V _{CE} =25V,		2500		pF
Output capacitance	Coss	$V_{GE}=0V$,		105		
Reverse transfer capacitance	Crss	f=1MHz		84		

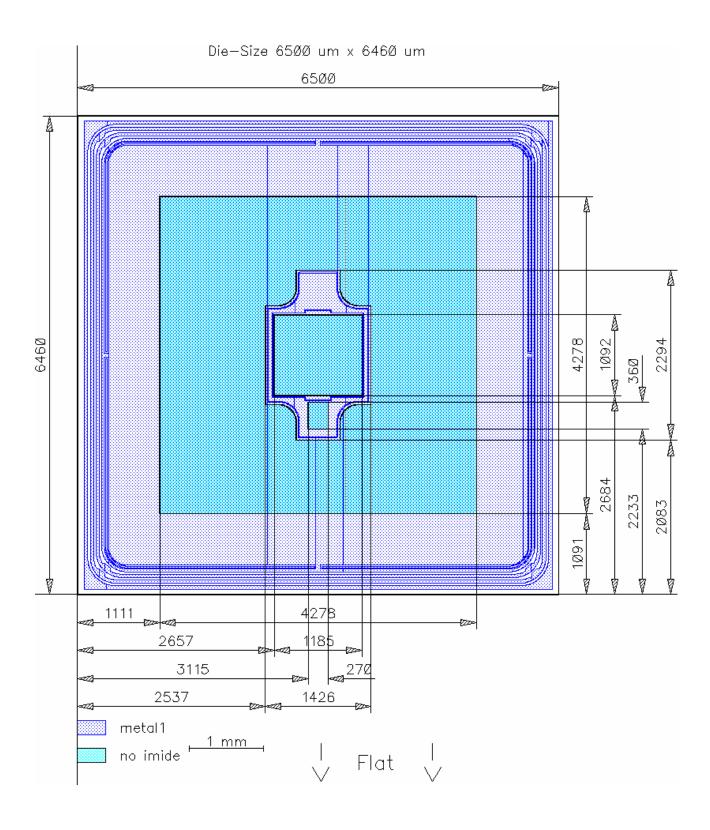
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions 1)	Value			Unit
raiametei			min.	typ.	max.	Joint
Turn-on delay time	$t_{d(on)}$	<i>T</i> _j =125°C		400		ns
Rise time	$t_{\rm r}$	V _{CC} =900V,		50		
Turn-off delay time	$t_{d(off)}$	I _C =29A, V _{GE} =-15/15V,		800		
Fall time	t_{f}	$R_{\rm G}$ = 18 Ω		300		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:	:	
This chip data sheet refers to the device data sheet		
DESCRIPTION:		
AQL 0,65 for visual inspection according to failur	re catalog	
Electrostatic Discharge Sensitive Device accordi	ing to MIL-STD 883	
Test-Normen Villach/Prüffeld		

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